

MOS FIELD EFFECT TRANSISTOR 2SK3304

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

The 2SK3304 is N-Channel MOS FET device that features a Low gate charge and excellent switching characteristics, and designed for high voltage applications such as switching power supply.

ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3304	TO-3P

FEATURES

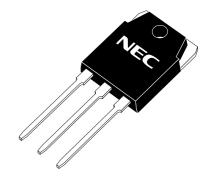
Low gate charge :
 Qg = 44 nC TYP. (VDD = 450 V, VGS = 10 V, ID = 7.0 A)

- Gate voltage rating: ±30 V
- Low on-state resistance :

RDS(on) = 2.0Ω MAX. (VGS = 10 V, ID = 4.0 A)

· Avalanche capability ratings

(TO-3P)



ABSOLUTE MAXIMUM RATINGS (TA = 25 °C)

Drain to Source Voltage	VDSS	900	V
Gate to Source Voltage	VGSS(AC)	±30	V
Drain Current (DC)	ID(DC)	±7	Α
Drain Current (Pulse) Note1	D(pulse)	±21	Α
Total Power Dissipation (Tc = 25°C)	P⊤	130	W
Total Power Dissipation (T _A = 25°C)	PT	3.0	W
Storage Temperature	Tstg	-55 to + 150	°C
Single Avalanche Current Note2	IAS	7	Α
Single Avalanche Energy Note2	Eas	147	mJ

Notes 1. PW \leq 10 μ s, Duty cycle \leq 1 %

2. Starting $T_{ch} = 25^{\circ}C$, $V_{DD} = 150 \text{ V}$, $R_G = 25 \Omega$, $V_{GS} = 20 \text{ V} \rightarrow 0 \text{ V}$

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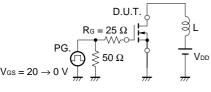
Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

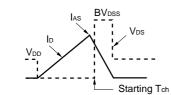


ELECTRICAL CHARACTERISTICS (TA = 25 °C)

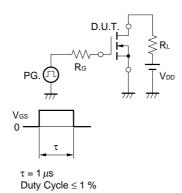
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain Leakage Current	IDSS	V _{DS} = 900 V, V _{GS} = 0 V			100	μΑ
Gate to Source Leakage Current	Igss	Vgs = ±30 V, Vps = 0 V			±100	nA
Gate to Source Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1.0 mA	2.5		3.5	V
Forward Transfer Admittance	yfs	V _{DS} = 20 V, I _D = 4.0 A	2.5	4.7		S
Drain to Source On-state Resistance	RDS(on)	Vgs = 10 V, ID = 4.0 A		1.6	2.0	Ω
Input Capacitance	Ciss	V _{DS} = 10 V		1300		pF
Output Capacitance	Coss	V _G S = 0 V		240		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		55		pF
Turn-on Delay Time	td(on)	V _{DD} = 150 V		20		ns
Rise Time	tr	ID = 4.0 A		44		ns
Turn-off Delay Time	td(off)	VGS(on) = 10 V		73		ns
Fall Time	tf	$R_G = 10 \Omega$, $R_L \cong 36 \Omega$		45		ns
Total Gate Charge	Q _G	V _{DD} = 450 V		44		nC
Gate to Source Charge	Qgs	Ves = 10 V		6		nC
Gate to Drain Charge	Q _{GD}	ID = 7.0 A		28		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 7.0 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	IF = 7.0 A, VGS = 0 V		2.4		μs
Reverse Recovery Charge	Qrr	di/dt = 50 A/μs		13.5		μC

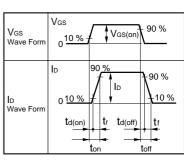
TEST CIRCUIT 1 AVALANCHE CAPABILITY



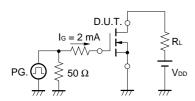


TEST CIRCUIT 2 SWITCHING TIME



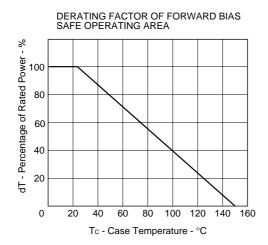


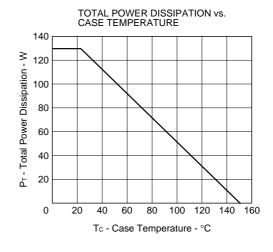
TEST CIRCUIT 3 GATE CHARGE



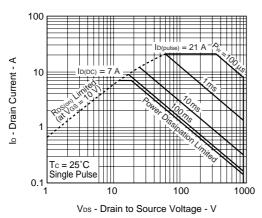


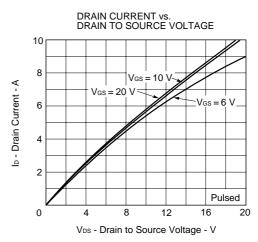
TYPICAL CHARACTERISTICS (TA = 25 °C)

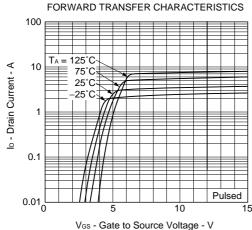




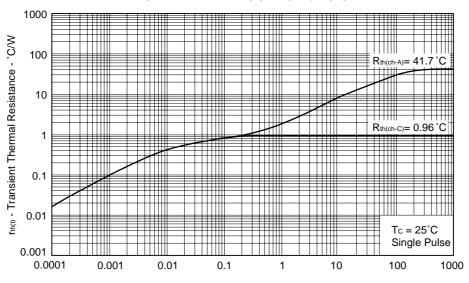
FORWARD BIAS SAFE OPERATING AREA



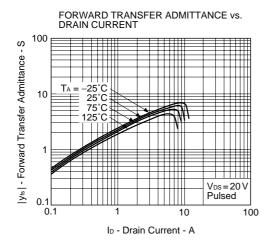


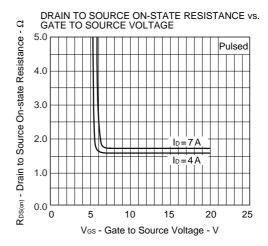


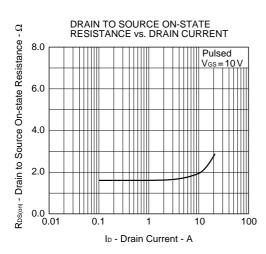
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

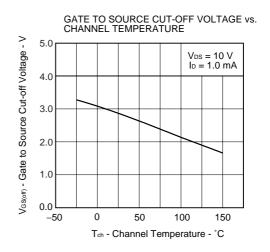


PW - Pulse Width - s

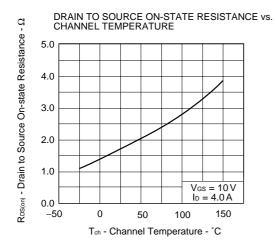


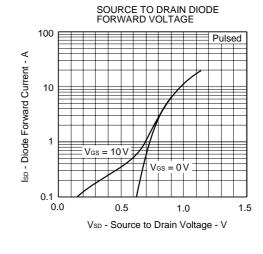


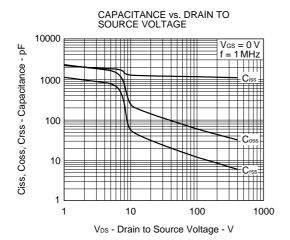


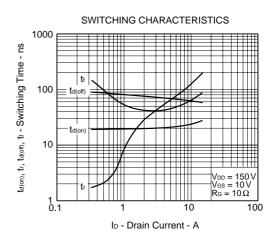


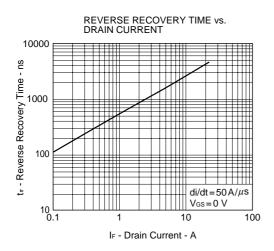


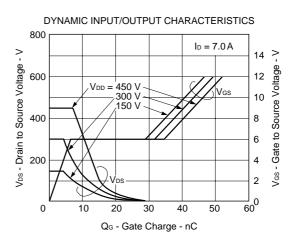


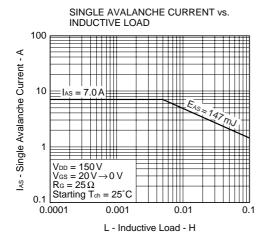


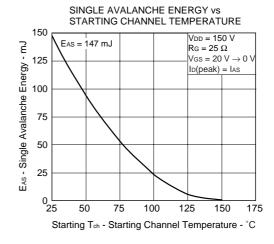








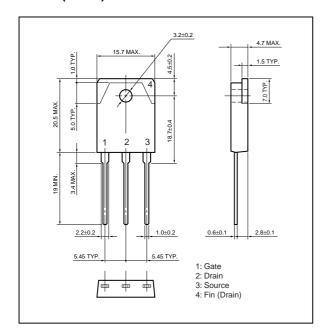




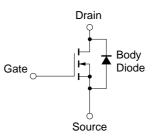


PACKAGE DRAWING (Unit: mm)

TO-3P (MP-88)



EQUIVALENT CIRCUIT



Remark Strong electric field, when exposed to this device, cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.

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